

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/766,817	SHINO ET AL.
	Examiner	Art Unit
	David Vu	2828

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
315	169.1	3/15/05	2)
315	169.3		
345	45		
345	76		